

# **AUTOMOTIVE GRADE**

# AUIRFS4010-7P

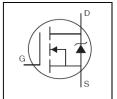
HEXFET® Power MOSFET

### **Features**

- Advanced Process Technology
- Ultra Low On-Resistance
- Enhanced dV/dT and dI/dT capability
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to Timax
- Lead-Free, RoHS Compliant
- Automotive Qualified \*

# Description

Specifically designed for Automotive applications, this HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in Automotive applications and a wide variety of other applications.



V <sub>DSS</sub>	100V
R <sub>DS(on)</sub> typ.	3.3mΩ
max.	4.0mΩ
I <sub>D</sub>	190A



G	D	S
Gate	Drain	Source

Page Part Number   Dockers Type		Standar	Orderable Part Number	
Base Part Number	Package Type	Form	Quantity	Orderable Part Number
AUIRFS4010-7P	D²Pak 7 Pin	Tube	50	AUIRFS4010-7P
AUIRF34010-7P	D Fak / PIII	Tape and Reel Left	800	AUIRFS4010-7TRL

#### **Absolute Maximum Ratings**

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified.

Symbol	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	190	
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	130	Α
I <sub>DM</sub>	Pulsed Drain Current ①	740	
P <sub>D</sub> @T <sub>C</sub> = 25°C	Maximum Power Dissipation	380	W
	Linear Derating Factor	2.5	W/°C
$V_{GS}$	Gate-to-Source Voltage	± 20	V
E <sub>AS</sub>	Single Pulse Avalanche Energy (Thermally Limited) ②	330	mJ
I <sub>AR</sub>	Avalanche Current ①	See Fig.14,15, 22a, 22b	Α
E <sub>AR</sub>	Repetitive Avalanche Energy ①		mJ
dv/dt	Peak Diode Recovery ③	26	V/ns
TJ	Operating Junction and	-55 to + 175	
$T_{STG}$	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	

### **Thermal Resistance**

Symbol	Parameter	Тур.	Max.	Units
$R_{ heta JC}$	Junction-to-Case ® ®		0.40	°C/W
$R_{ hetaJA}$	Junction-to-Ambient ⑦		40	C/VV

HEXFET® is a registered trademark of Infineon.

<sup>\*</sup>Qualification standards can be found at www.infineon.com



# Static @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	100			V	$V_{GS} = 0V, I_{D} = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.11		V/°C	Reference to 25°C, I <sub>D</sub> = 5mA ①
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance		3.3	4.0	mΩ	V <sub>GS</sub> = 10V, I <sub>D</sub> = 110A ④
$V_{GS(th)}$	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
gfs	Forward Trans conductance	210			S	V <sub>DS</sub> = 25V, I <sub>D</sub> = 110A
$R_G$	Gate Resistance		2.1		Ω	
	Drain to Course Leakers Current			20		$V_{DS} = 100V, V_{GS} = 0V$
I <sub>DSS</sub>	Drain-to-Source Leakage Current			250	μA	$V_{DS} = 100V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
ı	Gate-to-Source Forward Leakage			100	nA	V <sub>GS</sub> = 20V
I <sub>GSS</sub>	Gate-to-Source Reverse Leakage			-100	ПА	V <sub>GS</sub> = -20V

# Dynamic Electrical Characteristics @ T<sub>.1</sub> = 25°C (unless otherwise specified)

•		 	/		
$Q_g$	Total Gate Charge	 150	230		I <sub>D</sub> = 110A
$Q_{gs}$	Gate-to-Source Charge	 36			V <sub>DS</sub> = 50V V <sub>GS</sub> = 10V⊕
$Q_{gd}$	Gate-to-Drain Charge	 48		nC	V <sub>GS</sub> = 10V4
Q <sub>sync</sub>	Total Gate Charge Sync. (Q <sub>g</sub> - Q <sub>gd</sub> )	 102			
$t_{d(on)}$	Turn-On Delay Time	 19			$V_{DD} = 65V$
t <sub>r</sub>	Rise Time	 56		no	I <sub>D</sub> = 110A
$t_{d(off)}$	Turn-Off Delay Time	 100		ns	$R_G = 2.7\Omega$
$t_f$	Fall Time	 48			V <sub>GS</sub> = 10V4
C <sub>iss</sub>	Input Capacitance	 9830			$V_{GS} = 0V$
$C_{oss}$	Output Capacitance	 650			$V_{DS} = 50V$
C <sub>rss</sub>	Reverse Transfer Capacitance	 260		pF	f = 1.0MHz
Coss eff.(ER)	Effective Output Capacitance (Energy Related)	 730			V <sub>GS</sub> = 0V, V <sub>DS</sub> = 0V to 80V <sup>©</sup>
C <sub>oss eff.(TR)</sub>	Effective Output Capacitance (Time Related)	 740			V <sub>GS</sub> = 0V, V <sub>DS</sub> = 0V to 80V⑤

# **Diode Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current (Body Diode)			186		MOSFET symbol showing the
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ②			740		integral reverse p-n junction diode.
$V_{SD}$	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 110A, V_{GS} = 0V $
t <sub>rr</sub>	Reverse Recovery Time		60 67			$T_J = 25^{\circ}C$ $V_{DD} = 85V$ $T_J = 125^{\circ}C$ $I_F = 110A$ ,
Q <sub>rr</sub>	Reverse Recovery Charge		150 180		nC	$T_J = 25^{\circ}C$ di/dt = 100A/ $\mu$ s @ $T_J = 125^{\circ}C$
I <sub>RRM</sub>	Reverse Recovery Current		4.7			$T_J = 25^{\circ}C$
$t_{on}$	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )				

#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Limited by  $T_{Jmax}$ , starting  $T_J = 25$ °C, L = 0.052mH,  $R_G = 25\Omega$ ,  $I_{AS} = 110$ A,  $V_{GS} = 10$ V. Part not recommended for use above this value.
- $\label{eq:local_local_local_local} \ensuremath{ \Im } \quad I_{SD} \leq 110A, \ di/dt \leq 1310A/\mu s, \ V_{DD} \leq V_{(BR)DSS}, \ T_J \leq 175^{\circ}C.$
- 4 Pulse width  $\leq 400 \mu s$ ; duty cycle  $\leq 2\%$ .
- © Coss eff. (TR) is a fixed capacitance that gives the same charging time as Coss while VDS is rising from 0 to 80% VDSS.
- ©  $C_{oss}$  eff. (ER) is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .
- When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994

2015-10-27



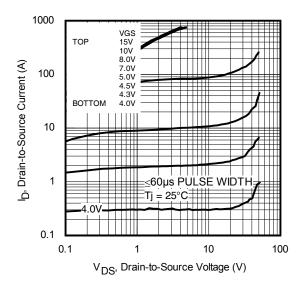


Fig. 1 Typical Output Characteristics

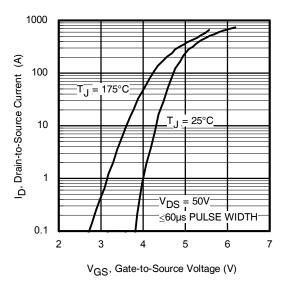


Fig. 3 Typical Transfer Characteristics

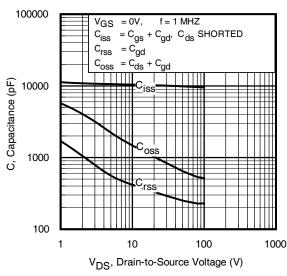


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

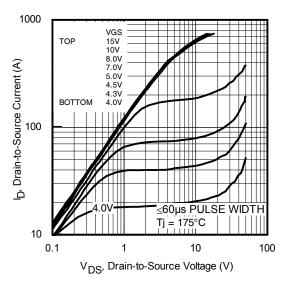


Fig. 2 Typical Output Characteristics

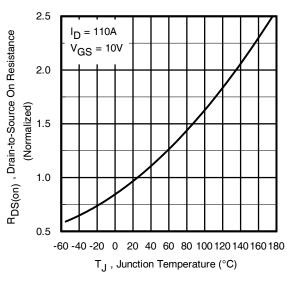


Fig. 4 Normalized On-Resistance vs. Temperature

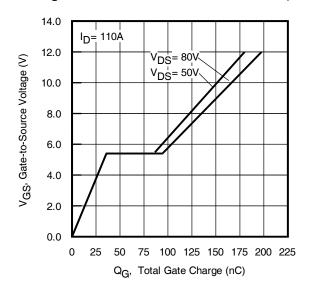


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage



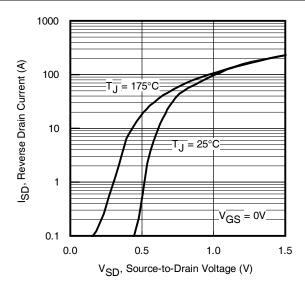


Fig. 7 Typical Source-to-Drain Diode Forward Voltage 200 180 160 Drain Current (A) 140 120 100 80 ؽ 60 40 20 0 150 175 25 50 75 100 125  $T_C$  , Case Temperature (°C)

Fig 9. Maximum Drain Current vs. Case Temperature

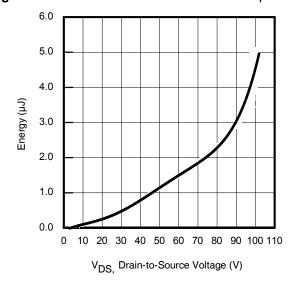


Fig 11. Typical Coss Stored Energy

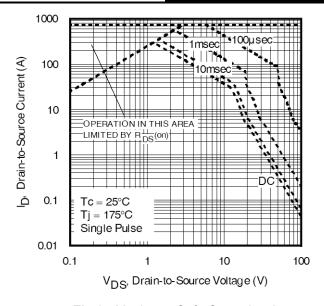


Fig 8. Maximum Safe Operating Area

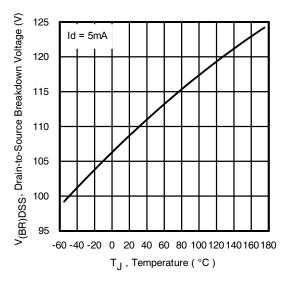


Fig 10. Drain-to-Source Breakdown Voltage

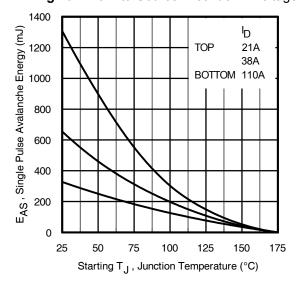


Fig 12. Maximum Avalanche Energy vs. Drain Current

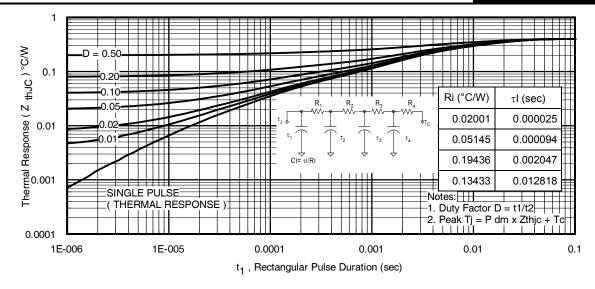


Fig 13. Maximum Effective Transient Thermal Impedance, Junction-to-Case

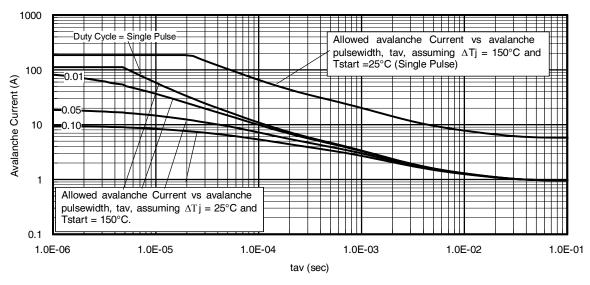


Fig 14. Avalanche Current vs. Pulse width

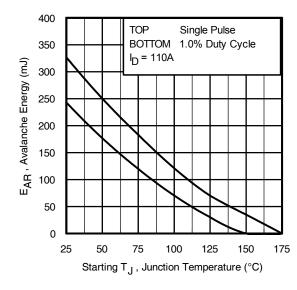


Fig 15. Maximum Avalanche Energy vs. Temperature

# Notes on Repetitive Avalanche Curves , Figures 14, 15: (For further info, see AN-1005 at www.infineon.com)

- Avalanche failures assumption:
   Purely a thermal phenomenon and failure occurs at a temperature far in excess of Tjmax. This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long as T<sub>jmax</sub> is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 18a, 18b.
- 4. PD (ave) = Average power dissipation per single avalanche pulse.
- BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. Iav = Allowable avalanche current.
- 7.  $\Delta T$  = Allowable rise in junction temperature, not to exceed  $T_{jmax}$  (assumed as 25°C in Figure 13, 14).

tav = Average time in avalanche.

D = Duty cycle in avalanche = tav ·f

ZthJC(D, tav) = Transient thermal resistance, see Figures 13)

$$\begin{split} P_{D \; (ave)} &= 1/2 \; (\; 1.3 \cdot BV \cdot I_{av}) = \Delta T/ \; Z_{thJC} \\ I_{av} &= 2\Delta T/ \; [1.3 \cdot BV \cdot Z_{th}] \\ E_{AS \; (AR)} &= P_{D \; (ave)} \cdot t_{av} \end{split}$$

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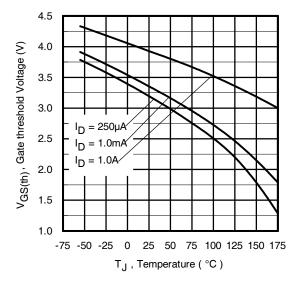


Fig 16. Threshold Voltage vs. Temperature

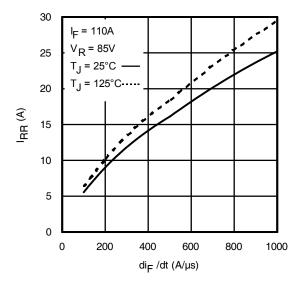


Fig. 18 - Typical Recovery Current vs. dif/dt

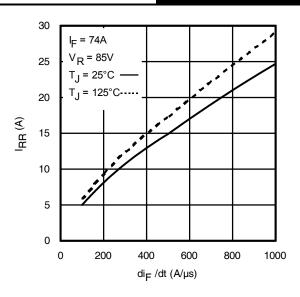


Fig. 17 - Typical Recovery Current vs. dif/dt

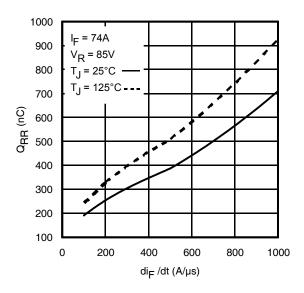


Fig. 19 - Typical Stored Charge vs. dif/dt

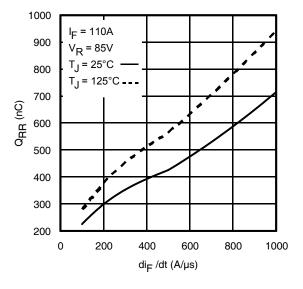


Fig. 20 - Typical Stored Charge vs. dif/dt



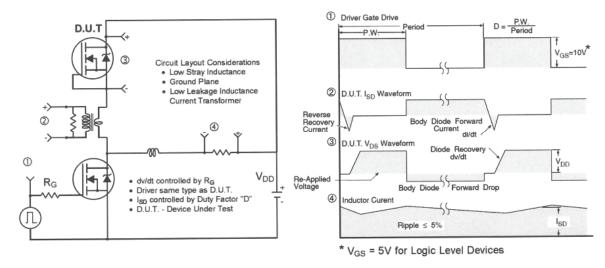


Fig 21. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

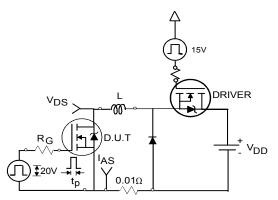


Fig 22a. Unclamped Inductive Test Circuit

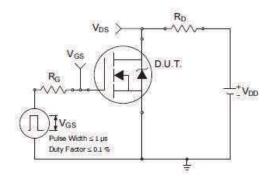


Fig 23a. Switching Time Test Circuit

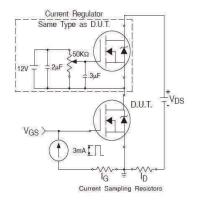


Fig 24a. Gate Charge Test Circuit

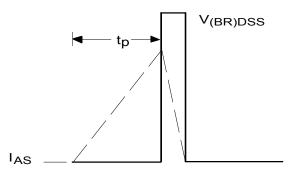


Fig 22b. Unclamped Inductive Waveforms

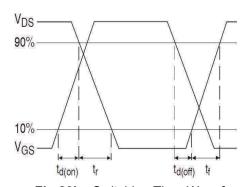


Fig 23b. Switching Time Waveforms

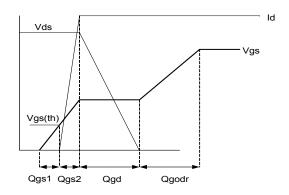
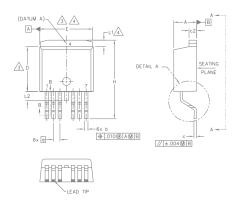
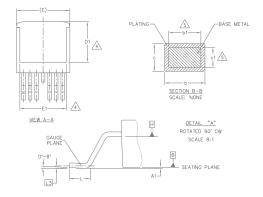


Fig 24b. Gate Charge Waveform



# D<sup>2</sup>Pak - 7 Pin Package Outline (Dimensions are shown in millimeters (inches))





S	DIMENSIONS					
М В О	MILLIM	ETERS	INC	HES	N O T E S	
L	MIN.	MAX.	MIN.	MAX.	E S	
А	4.06	4.83	.160	.190		
Α1	_	0.254	_	.010		
Ь	0.51	0.99	.020	.036		
b1	0.51	0.89	.020	.032	5	
С	0.38	0.74	.015	.029		
с1	0.38	0.58	.015	.023	5	
c2	1.14	1.65	.045	.065		
D	8.38	9.65	.330	.380	3	
D1	6.86	7.42	.270	.292	4	
Ε	9.65	10.54	.380	.415	3,4	
E1	6.22	8.48	.245	.334	4	
е	1.27 BSC		.050	BSC		
Н	14.61	15.88	.575	.625		
L	1.78	2.79	.070	.110		
L1	_	1.68	_	.066	4	
L2	-	1.78	_	.070		
L3	0.25 BSC		.010	BSC	1	

#### NOTES:

- 1. DIMENSIONING AND TOLERANCING AS PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

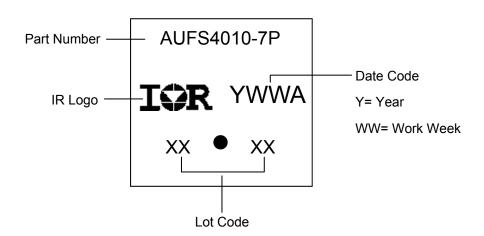
O.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

5. DIMENSION 61 AND c1 APPLY TO BASE METAL ONLY.

- 6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 7. CONTROLLING DIMENSION: INCH.
- 8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-263CB. EXCEPT FOR DIMS. E, E1 & D1.

D<sup>2</sup>Pak - 7 Pin Part Marking Information



Note: For the most current drawing please refer to IR website at <a href="http://www.irf.com/package/">http://www.irf.com/package/</a>



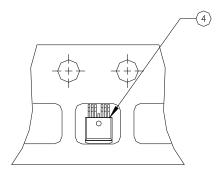
# D<sup>2</sup>Pak - 7 Pin Tape and Reel

NOTES, TAPE & REEL, LABELLING:

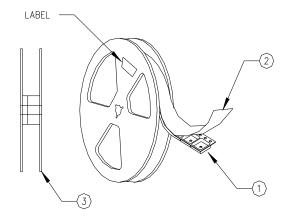
- 1. TAPE AND REEL.
  - 1.1 REEL SIZE 13 INCH DIAMETER.
  - 1.2 EACH REEL CONTAINING 800 DEVICES.
  - 1.3 THERE SHALL BE A MINIMUM OF 42 SEALED POCKETS CONTAINED IN THE LEADER AND A MINIMUM OF 15 SEALED POCKETS IN THE TRAILER.
  - 1.4 PEEL STRENGTH MUST CONFORM TO THE SPEC. NO. 71-9667.
  - 1.5 PART ORIENTATION SHALL BE AS SHOWN BELOW.
  - 1.6 REEL MAY CONTAIN A MAXIMUM OF TWO UNIQUE LOT CODE/DATE CODE COMBINATIONS.

    REWORKED REELS MAY CONTAIN A MAXIMUM OF THREE UNIQUE LOT CODE/DATE CODE COMBINATIONS.

    HOWEVER, THE LOT CODES AND DATE CODES WITH THEIR RESPECTIVE QUANTITIES SHALL APPEAR ON THE BAR CODE LABEL FOR THE AFFECTED REEL.



- 2. LABELLING (REEL AND SHIPPING BAG).
  - 2.1 CUST. PART NUMBER (BAR CODE): IRFXXXXSTRL-7P
  - 2.2 CUST. PART NUMBER (TEXT CODE): IRFXXXXSTRL-7P
  - 2.3 I.R. PART NUMBER: IRFXXXXSTRL-7P
  - 2.4 QUANTITY:
  - 2.5 VENDOR CODE: IR
  - 2.6 LOT CODE:
  - 2.7 DATE CODE:



Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



#### **Qualification Information**

		Automotive (per AEC-Q101)				
Qualificat		Comments: This part number(s) passed Automotive qualification. Infineon's Industrial and Consumer qualification level is granted by extension of the higher Automotive level.				
Moisture	Sensitivity Level	D <sup>2</sup> -Pak 7 Pin	MSL1			
	Na alaina Madal		Class M4 (+/- 800V) <sup>†</sup>			
	Machine Model	AEC-Q101-002				
ECD	Human Dady Madal	Class H3A (+/- 6000V) <sup>†</sup>				
ESD	Human Body Model	AEC-Q101-001				
	Charged Device Model	Class C5 (+/- 2000V) <sup>†</sup>				
	Charged Device Model		AEC-Q101-005			
RoHS Cor	mpliant	Yes				

<sup>†</sup> Highest passing voltage.

# **Revision History**

Date	Comments			
3/10/2014 • Updated fig.8 SOA curve on page 5				
3/10/2014	Updated data sheet with new IR corporate template			
10/27/2015	Updated datasheet with corporate template			
10/2//2015	Corrected ordering table on page 1.			

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